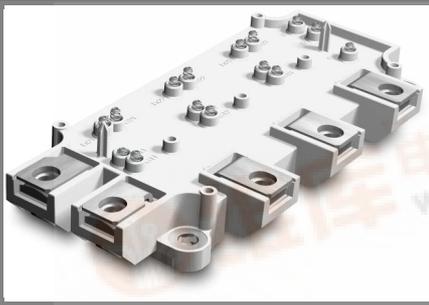


SEMIX 101GD066HDS



SEMIX[®] 13s

Trench IGBT Modules

SEMIX 101GD066HDS

Target Data

Features

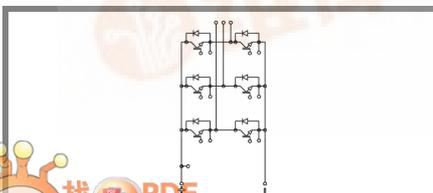
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient

Typical Applications

- Matrix Converter
- Resonant Inverter
- Current Source Inverter

Remarks

- Case temperatur limited to $T_C=125^{\circ}C$ max.
- Product reliability results are valid for $T_J=150^{\circ}C$
- SC data: $t_p \leq 6 \mu s$; $V_{GE} \leq 15 V$; $T_J = 150^{\circ}C$; $V_{CC} = 360 V$

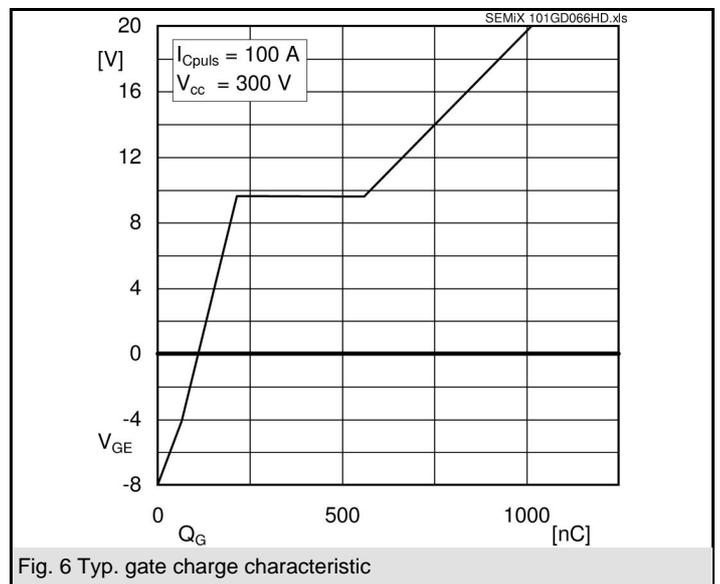
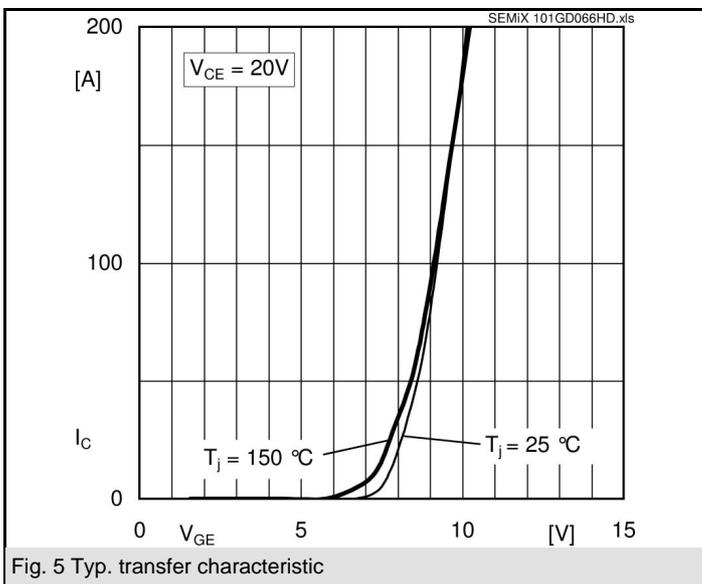
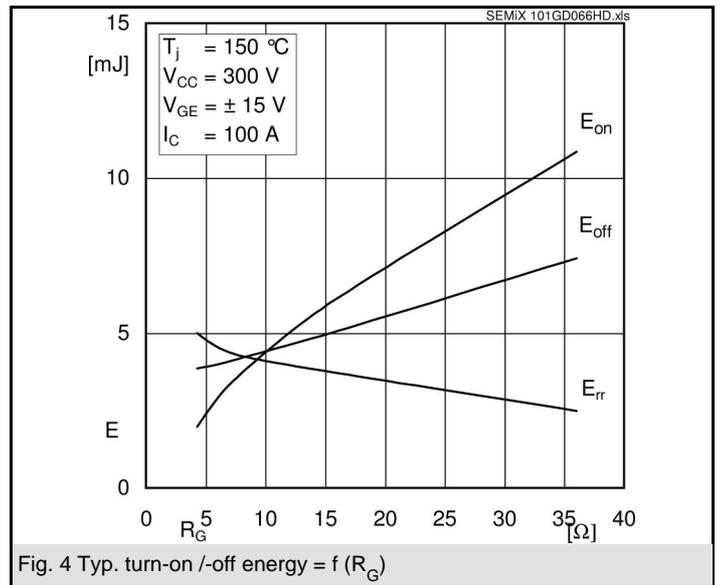
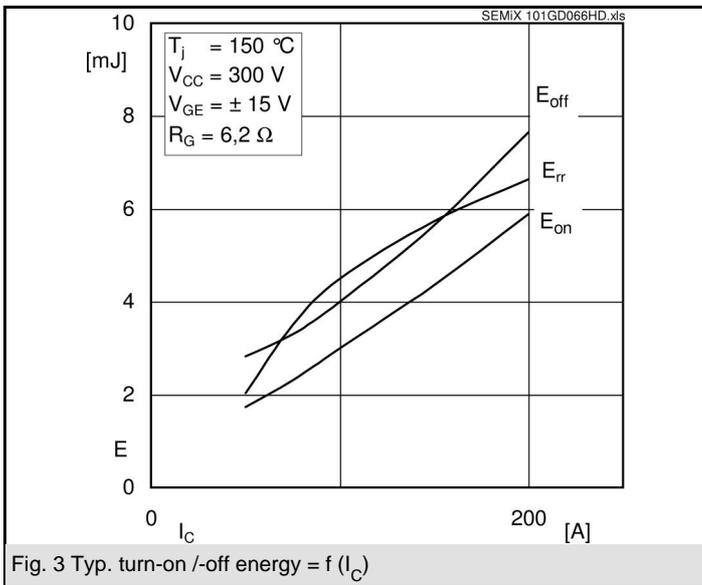
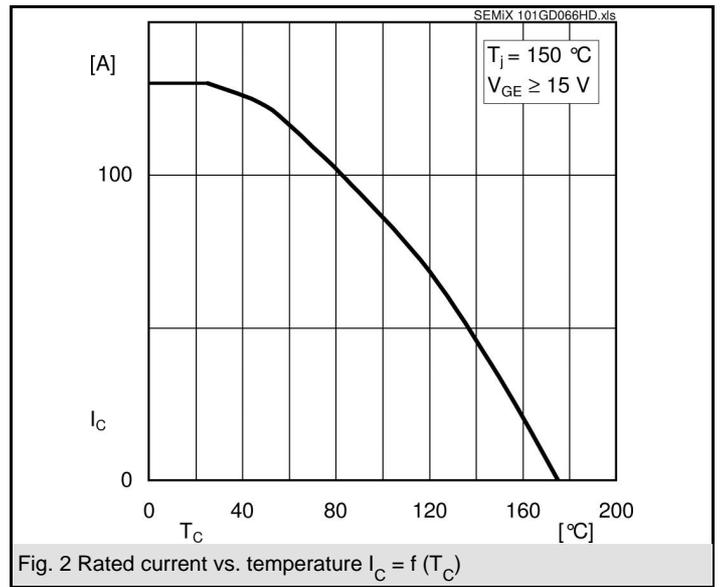
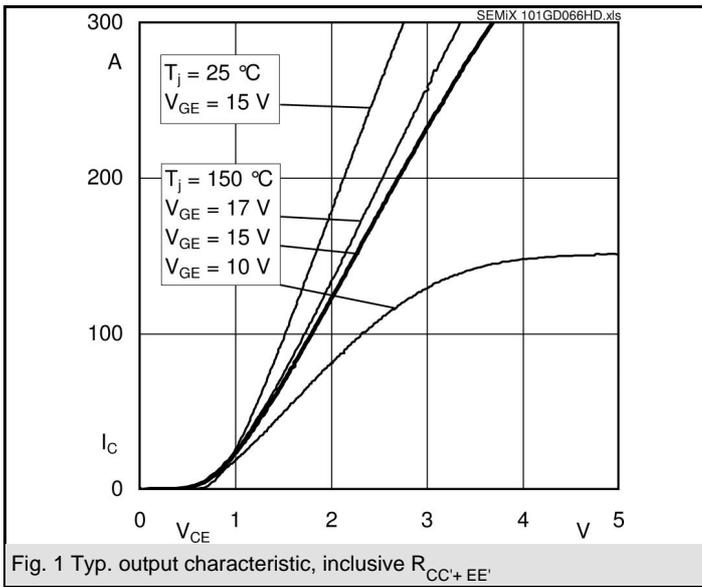


Absolute Maximum Ratings		$T_{case} = 25^{\circ}C$, unless otherwise specified	
Symbol	Conditions	Values	Units
IGBT			
V_{CES}		600	V
I_C	$T_C = 25 (80)^{\circ}C, T_J = 150^{\circ}C$	120 (90)	A
I_C	$T_C = 25 (80)^{\circ}C, T_J = 175^{\circ}C$	130 (100)	A
I_{CRM}	$t_p = 1 ms$	200	A
V_{GES}		± 20	V
$T_J, (T_{stg})$		- 40 ... + 175 (125)	$^{\circ}C$
V_{isol}	AC, 1 min.	4000	V
Inverse diode			
I_F	$T_C = 25 (80)^{\circ}C, T_J = 150^{\circ}C$	90 (60)	A
I_F	$T_C = 25 (80)^{\circ}C, T_J = 175^{\circ}C$	110 (80)	A
I_{FRM}	$t_p = 1 ms$	200	A
I_{FSM}	$t_p = 10 ms; sin.; T_J = 25^{\circ}C$	500	A

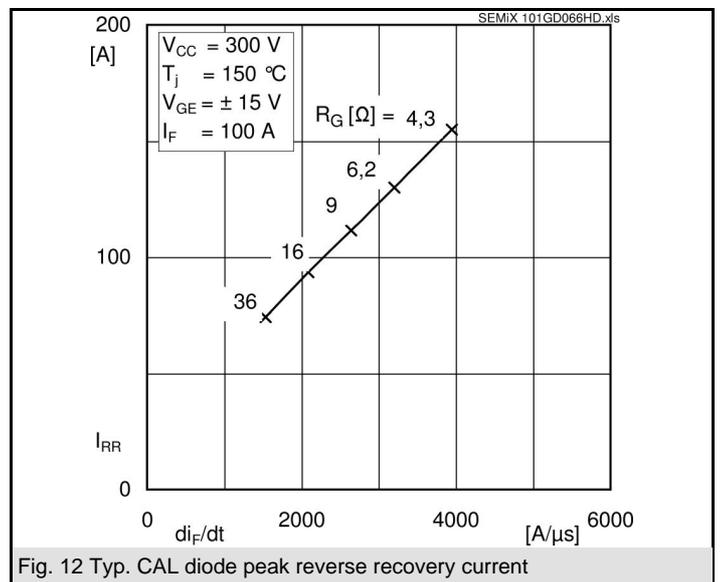
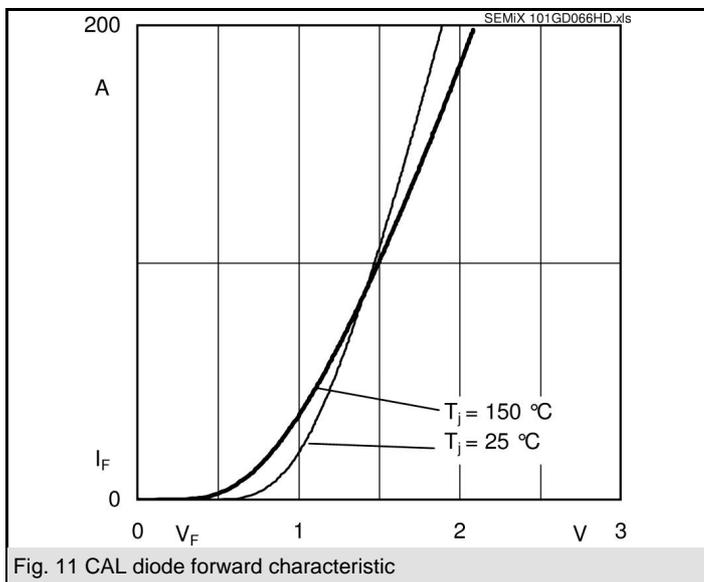
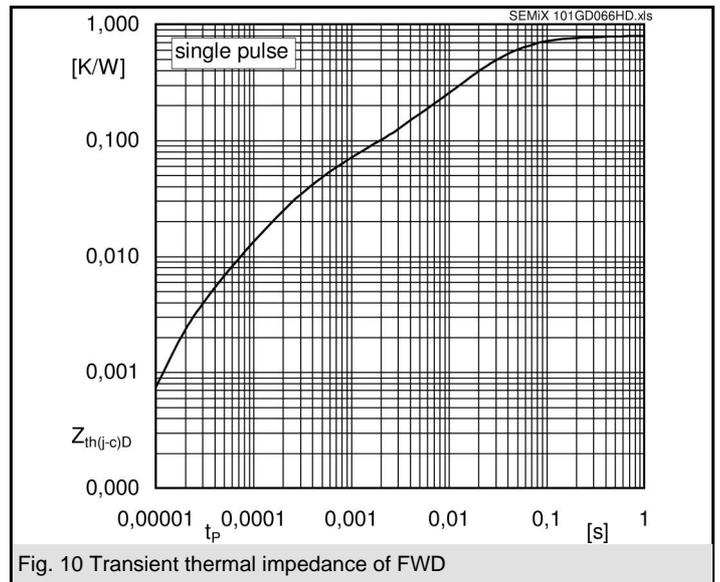
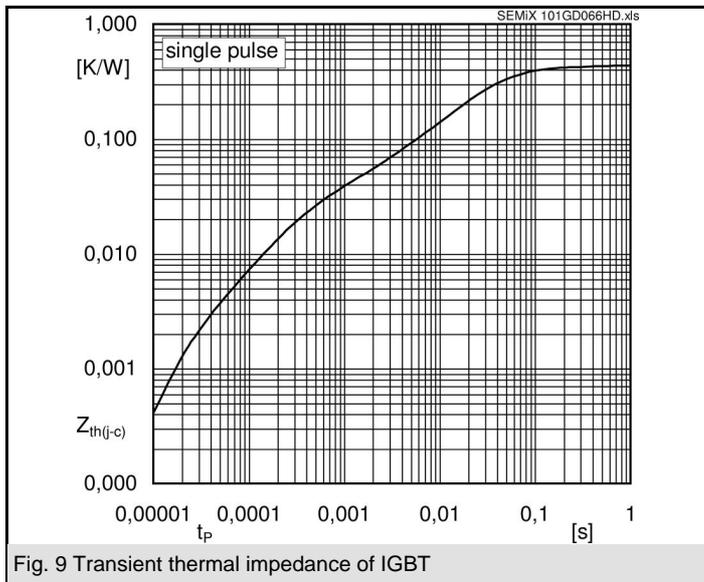
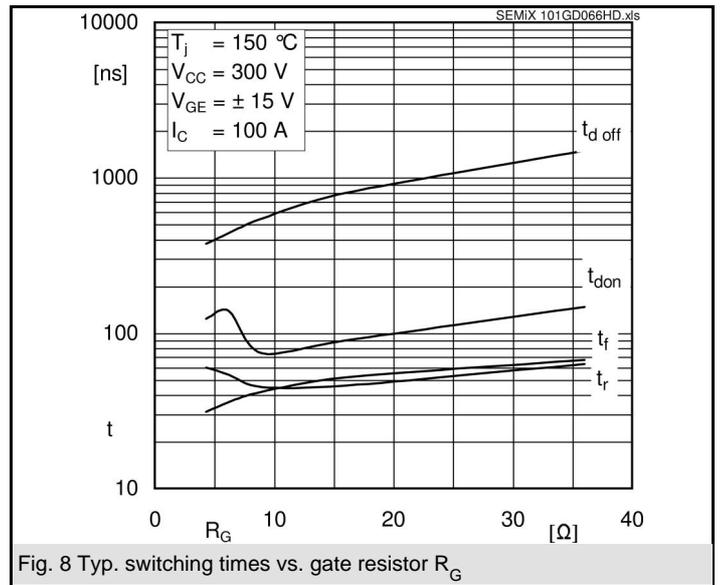
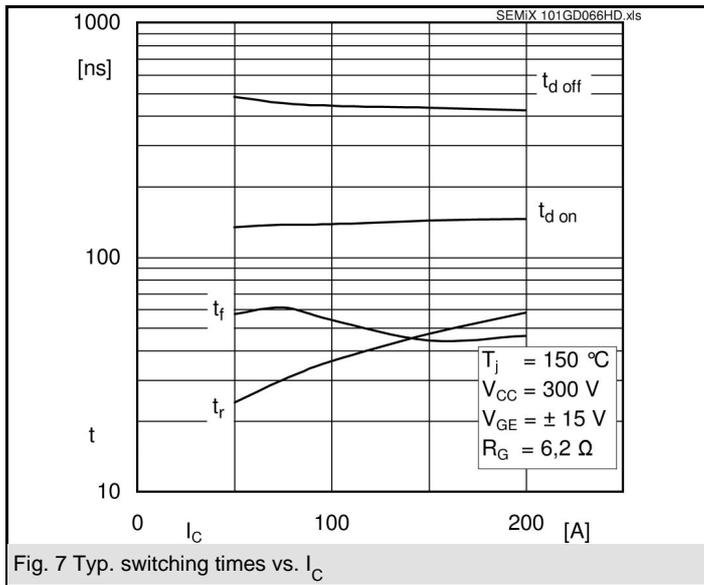
Characteristics		$T_{case} = 25^{\circ}C$, unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
IGBT					
$V_{GE(th)}$	$V_{GE} = V_{CES}, I_C = 3 mA$		5,8		V
I_{CES}	$V_{GE} = 0, V_{CE} = V_{CES}, T_J = 25 (^{\circ})^{\circ}C$			0,15	mA
$V_{CE(TO)}$	$T_J = 25 (150)^{\circ}C$		0,9 (0,85)	1 (0,9)	V
r_{CE}	$V_{GE} = 15 V, T_J = 25 (150)^{\circ}C$		5,5 (8,5)	9 (12)	m Ω
$V_{CE(sat)}$	$I_{Cnom} = 100 A, V_{GE} = 15 V, T_J = 25 (150)^{\circ}C, chip level$		1,45 (1,7)	1,9 (2,1)	V
C_{ies}	under following conditions		6,1		nF
C_{oes}	$V_{GE} = 0, V_{CE} = 25 V, f = 1 MHz$		0,39		nF
C_{res}			0,18		nF
L_{CE}			20		nH
$R_{CC'+EE'}$	terminal-chip, $T_C = 25 (125)^{\circ}C$		0,7 (1)		m Ω
$t_{d(on)}/t_r$	$V_{CC} = 300 V, I_{Cnom} = 100 A$		138 / 36		ns
$t_{d(off)}/t_f$	$V_{GE} = \pm 15 V$		442 / 54		ns
$E_{on} (E_{off})$	$R_{Gon} = R_{Goff} = 6 \Omega, T_J = 150^{\circ}C$		2,5 (4,5)		mJ
Inverse diode					
$V_F = V_{EC}$	$I_{Fnom} = 100 A; V_{GE} = 0 V; T_J = 25 (150)^{\circ}C, chip level$		1,4 (1,4)	1,6	V
$V_{(TO)}$	$T_J = 25 (150)^{\circ}C$		1 (0,85)	1,1	V
r_T	$T_J = 25 (150)^{\circ}C$		4 (5,5)	5	m Ω
I_{RRM}	$I_{Fnom} = 100 A; T_J = 25 (150)^{\circ}C$		130		A
Q_{rr}	$di/dt = 3200 A/\mu s$		18		μC
E_{rr}	$V_{GE} = -15 V$		4,5		mJ
Thermal characteristics					
$R_{th(j-c)}$	per IGBT			0,44	K/W
$R_{th(j-c)D}$	per Inverse Diode			0,8	K/W
$R_{th(j-c)FD}$	per FWD				K/W
$R_{th(c-s)}$	per module		0,04		K/W
Temperature sensor					
R_{25}	$T_C = 25^{\circ}C$		5 \pm 5%		k Ω
$B_{25/85}$	$R_2 = R_1 \exp[B(1/T_2 - 1/T_1)]; T[K]; B$		3420		K
Mechanical data					
M_s/M_t	to heatsink (M5) / for terminals (M6)	3/2,5		5 / 5	Nm
w			290		g



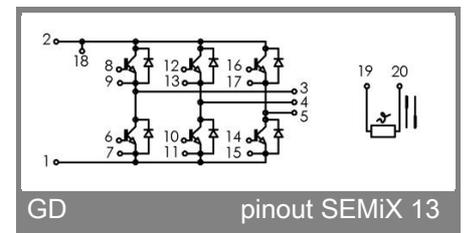
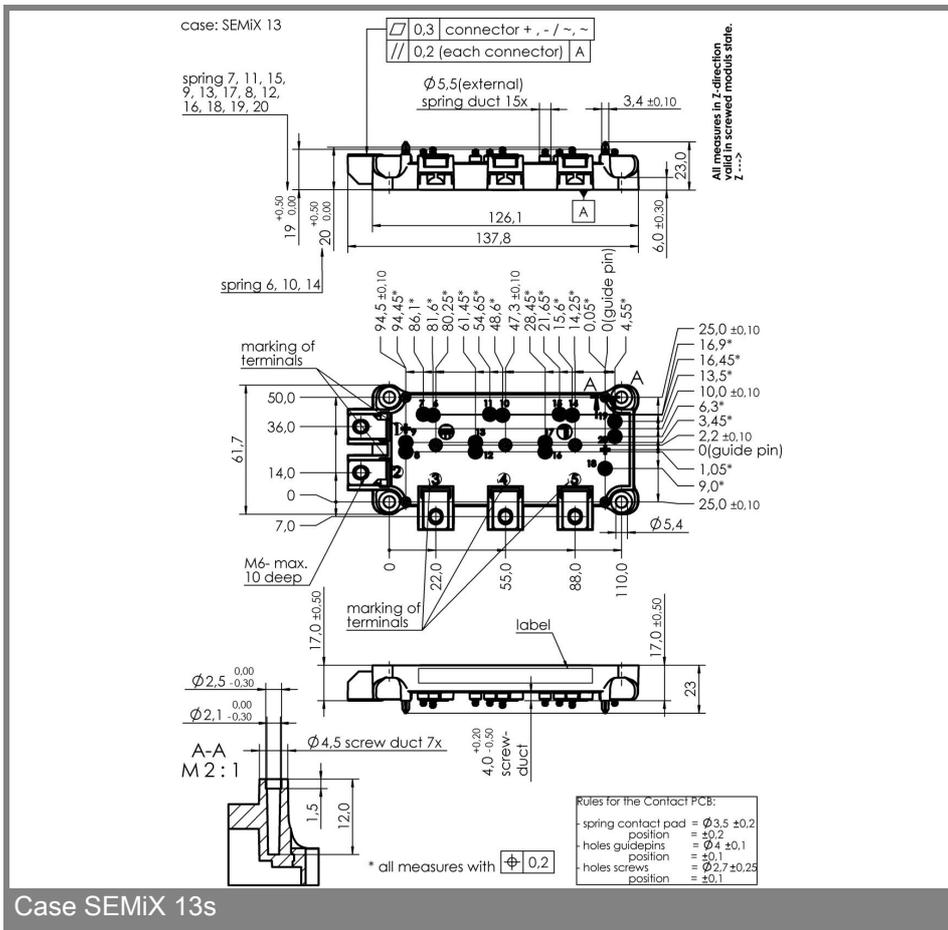
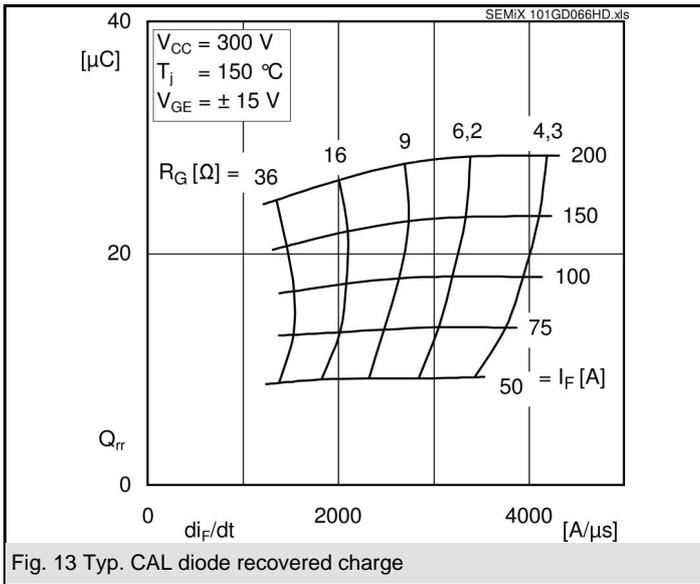
SEMIX 101GD066HDs



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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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